## Application/Control No. Applicant(s)/Patent Under Reexamination 10/720,342 LEE ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Thuy V. Tran 2821

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0207339 A1	10-2004	Lin et al.	315/291
*	В	US-6,680,588 B2	01-2004	Park et al.	315/312
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## **FOREIGN PATENT DOCUMENTS**

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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.